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1. **An efficient BIST method for distributed small buffers**
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   Very Large Scale Integration (VLSI) Systems, IEEE Transactions on
   Volume 10, Issue 4, Aug. 2002 Page(s):512 - 515
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An efficient BIST method for distributed small buffers

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Abstract
In this work, we propose a new built-in self-testing (BIST) method that is able to concurrently test a set of spatially distributed embedded-memory modules with different sizes. Using the concept of **redundant** read-write operations, we develop a new march method, called RSMarch, to efficiently test each memory module. The new method has the advantages of low hardware overhead, short test time, and high-fault coverage. The total test time is dominated by large-size modules. To further reduce the test time, we also propose a split-mode test method to **virtually** partition each large memory array into smaller modules, which can be tested simultaneously.

Index Terms
Inspec

Controlled Indexing

VLSI buffer **storage** built-in self test integrated circuit testing integrated memory circuits logic testing system-on-chip

Non-controlled Indexing

BIST method RSMarch SOC testing built-in self-testing concurrent testing distributed small buffers high-fault coverage low hardware overhead march method **redundant** read-write operations serial interface technique short test time spatially distributed embedded-memory modules split-mode test method system on chip testing

Author Keywords
Not Available

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On page(s): 1381- 1390, Volume: 52, Issue: 5, Oct. 2003
Abstract | Full Text: PDF (412)

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L2	((storage or disk or disc) near5 controller) same virtual$7 same redundant	138	L2
DB=DWPI; PLUR=YES; OP=OR			
L1	((storage or disk or disc) near5 controller) same virtual$7 same redundant	7	L1

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Search Results -

Terms	Documents
L2 and "point-to-point"	0

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Search: L4

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L4	L2 and "point-to-point"	0	L4
DB=PGPB,USPT,USOC; PLUR=YES; OP=OR			
L3	L2 and "point-to-point"	7	L3
L2	((storage or disk or disc) near5 controller) same virtual$7 same redundant	138	L2
DB=DWPI; PLUR=YES; OP=OR			
L1	((storage or disk or disc) near5 controller) same virtual$7 same redundant	7	L1

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